

## 74ABT240 Octal Buffer/Line Driver with 3-STATE Outputs

### General Description

The ABT240 is an inverting octal buffer and line driver designed to be employed as a memory address driver, clock driver and bus oriented transmitter or receiver which provides improved PC board density.

### Features

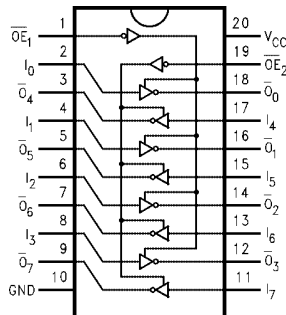
- Output sink capability of 64 mA, source capability of 32 mA
- Guaranteed latchup protection
- High impedance glitch free bus loading during entire power up and power down cycle
- Nondestructive hot insertion capability

### Ordering Code:

Order Number	Package Number	Package Description
74ABT240CSC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide Body
74ABT240CSJ	M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74ABT240CMSA	MSA20	20-Lead Shrink Small Outline Package (SSOP), EIAJ TYPE II, 5.3mm Wide
74ABT240CMTC	MTC20	20-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide

Device also available in Tape and Reel. Specify by appending suffix letter "X" to the ordering code.

### Connection Diagram



### Pin Descriptions

Pin Names	Description
$\overline{OE}_1, \overline{OE}_2$	3-STATE Output Enable Inputs
$I_0-I_7$	Inputs
$\overline{O}_0-\overline{O}_7$	Outputs

### Truth Tables

Inputs		Outputs (Pins 12, 14, 16, 18)
$\overline{OE}_1$	$I_n$	
L	L	H
L	H	L
H	X	Z

Inputs		Outputs (Pins 3, 5, 7, 9)
$\overline{OE}_2$	$I_n$	
L	L	H
L	H	L
H	X	Z

H = HIGH Voltage Level  
 L = LOW Voltage Level  
 X = Immaterial  
 Z = High Impedance

Absolute Maximum Ratings (Note 1)		Recommended Operating Conditions	
Storage Temperature	-65°C to +150°C	Free Air Ambient Temperature	-40°C to +85°C
Junction Temperature under Bias	-55°C to +150°C	Supply Voltage	+4.5V to +5.5V
V <sub>CC</sub> Pin Potential to Ground Pin	-0.5V to +7.0V	Minimum Input Edge Rate ( $\Delta V/\Delta t$ )	
Input Voltage (Note 2)	-0.5V to +7.0V	Data Input	50 mV/ns
Input Current (Note 2)	-30 mA to +5.0 mA	Enable Input	20 mV/ns
Voltage Applied to Any Output in the Disabled or Power-Off State	-0.5V to 5.5V		
in the HIGH State	-0.5V to V <sub>CC</sub>		
Current Applied to Output in LOW State (Max)	twice the rated I <sub>OL</sub> (mA)		
DC Latchup Source Current (Across Comm Operating Range)	-150 mA		
Over Voltage Latchup (I/O)	10V		

**Note 1:** Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

**Note 2:** Either voltage limit or current limit is sufficient to protect inputs.

### DC Electrical Characteristics

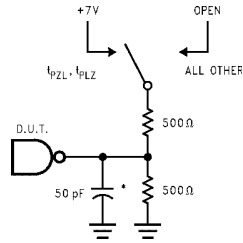
Symbol	Parameter	Min	Typ	Max	Units	V <sub>CC</sub>	Conditions
V <sub>IH</sub>	Input HIGH Voltage	2.0			V		Recognized HIGH Signal
V <sub>IL</sub>	Input LOW Voltage			0.8	V		Recognized LOW Signal
V <sub>CD</sub>	Input Clamp Diode Voltage			-1.2	V	Min	I <sub>IN</sub> = -18 mA
V <sub>OH</sub>	Output HIGH Voltage	2.5			V	Min	I <sub>OH</sub> = -3 mA
		2.0			V	Min	I <sub>OH</sub> = -32 mA
V <sub>OL</sub>	Output LOW Voltage			0.55	V	Min	I <sub>OL</sub> = 64 mA
I <sub>IH</sub>	Input HIGH Current			1	μA	Max	V <sub>IN</sub> = 2.7V (Note 3)
				1	μA	Max	V <sub>IN</sub> = V <sub>CC</sub>
I <sub>BVI</sub>	Input HIGH Current Breakdown Test			7	μA	Max	V <sub>IN</sub> = 7.0V
I <sub>IL</sub>	Input LOW Current			-1	μA	Max	V <sub>IN</sub> = 0.5V (Note 3)
				-1	μA	Max	V <sub>IN</sub> = 0.0V
V <sub>ID</sub>	Input Leakage Test	4.75			V	0.0	I <sub>ID</sub> = 1.9 μA All Other Pins Grounded
I <sub>OZH</sub>	Output Leakage Current			10	μA	0 - 5.5V	V <sub>OUT</sub> = 2.7V; $\overline{OE}_n = 2.0V$
I <sub>OZL</sub>	Output Leakage Current			-10	μA	0 - 5.5V	V <sub>OUT</sub> = 0.5V; $\overline{OE}_n = 2.0V$
I <sub>OS</sub>	Output Short-Circuit Current	-100		-275	mA	Max	V <sub>OUT</sub> = 0.0V
I <sub>CEx</sub>	Output HIGH Leakage Current			50	μA	Max	V <sub>OUT</sub> = V <sub>CC</sub>
I <sub>ZZ</sub>	Bus Drainage Test			100	μA	0.0	V <sub>OUT</sub> = 5.5V; All Others GND
I <sub>CCH</sub>	Power Supply Current			50	μA	Max	All Outputs HIGH
I <sub>CCL</sub>	Power Supply Current			30	mA	Max	All Outputs LOW
I <sub>CCZ</sub>	Power Supply Current			50	μA	Max	$\overline{OE}_n = V_{CC}$ ; All Others at V <sub>CC</sub> or Ground
I <sub>CCt</sub>	Additional I <sub>CC</sub> /Input	Outputs Enabled		1.5	mA	Max	V <sub>I</sub> = V <sub>CC</sub> - 2.1V Enable Input V <sub>I</sub> = V <sub>CC</sub> - 2.1V Data Input V <sub>I</sub> = V <sub>CC</sub> - 2.1V All Others at V <sub>CC</sub> or Ground
		Outputs 3-STATE		1.5	mA		
		Outputs 3-STATE		50	μA		
I <sub>CCD</sub>	Dynamic I <sub>CC</sub> (Note 3)	No Load		0.1	mA/ MHz	Max	Outputs Open $\overline{OE}_n = GND$ , (Note 4) One Bit Toggling, 50% Duty Cycle

**Note 3:** Guaranteed, but not tested.

**Note 4:** For 8 bits toggling, I<sub>CCD</sub> < 0.8 mA/MHz.

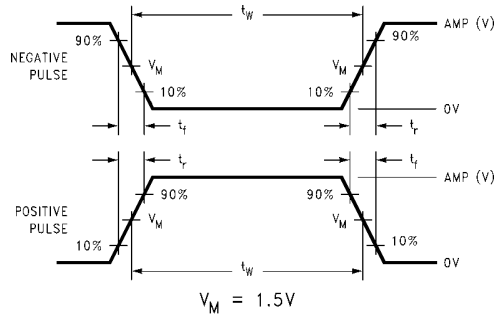
AC Electrical Characteristics									
Symbol	Parameter	T <sub>A</sub> = +25°C V <sub>CC</sub> = +5V C <sub>L</sub> = 50 pF			T <sub>A</sub> = -55°C to +125°C V <sub>CC</sub> = 4.5V–5.5V C <sub>L</sub> = 50 pF		T <sub>A</sub> = -40°C to +85°C V <sub>CC</sub> = 4.5V–5.5V C <sub>L</sub> = 50 pF		Units
		Min	Typ	Max	Min	Max	Min	Max	
t <sub>PLH</sub>	Propagation Delay	1.0		4.8	0.8	5.5	1.0	4.8	ns
t <sub>PHL</sub>	Data to Outputs	1.6		4.8	1.0	5.5	1.6	4.8	
t <sub>PZH</sub>	Output Enable	1.1		6.2	0.8	7.5	1.1	6.2	ns
t <sub>PZL</sub>	Time	1.1		6.2	0.8	7.7	1.1	6.2	
t <sub>PHZ</sub>	Output Disable	1.8		6.4	1.0	7.5	1.8	6.4	ns
t <sub>PLZ</sub>	Time	1.6		5.8	1.0	7.2	1.6	5.8	
Capacitance									
Symbol	Parameter	Typ	Units	Conditions T <sub>A</sub> = 25°C					
C <sub>IN</sub>	Input Capacitance	5.0	pF	V <sub>CC</sub> = 0V					
C <sub>OUT</sub> (Note 5)	Output Capacitance	9.0	pF	V <sub>CC</sub> = 5.0V					
<b>Note 5:</b> C <sub>OUT</sub> is measured at frequency f = 1 MHz, per MIL-STD-883, Method 3012.									

### AC Loading



\*Includes jig and probe capacitance

**Standard AC Test Load**

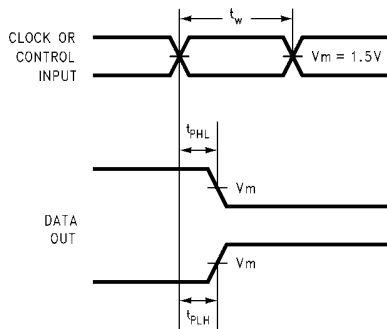


**Test Input Signal Levels**

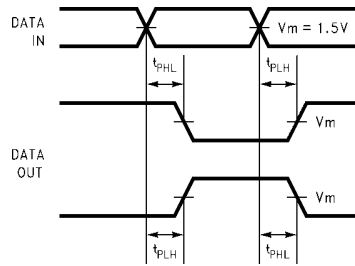
Amplitude	Rep. Rate	$t_w$	$t_r$	$t_f$
3.0V	1 MHz	500 ns	2.5 ns	2.5 ns

Test Input Signal Requirements

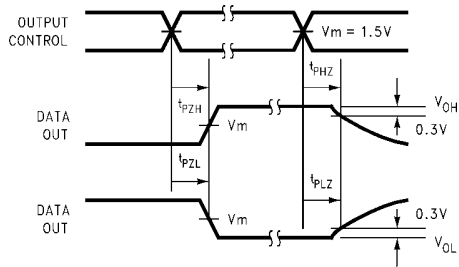
### AC Waveforms



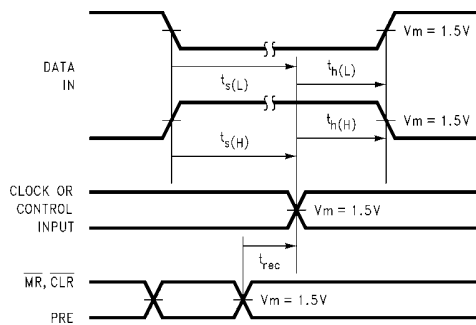
**Propagation Delay, Pulse Width Waveforms**



**Propagation Delay Waveforms for Inverting and Non-Inverting Functions**

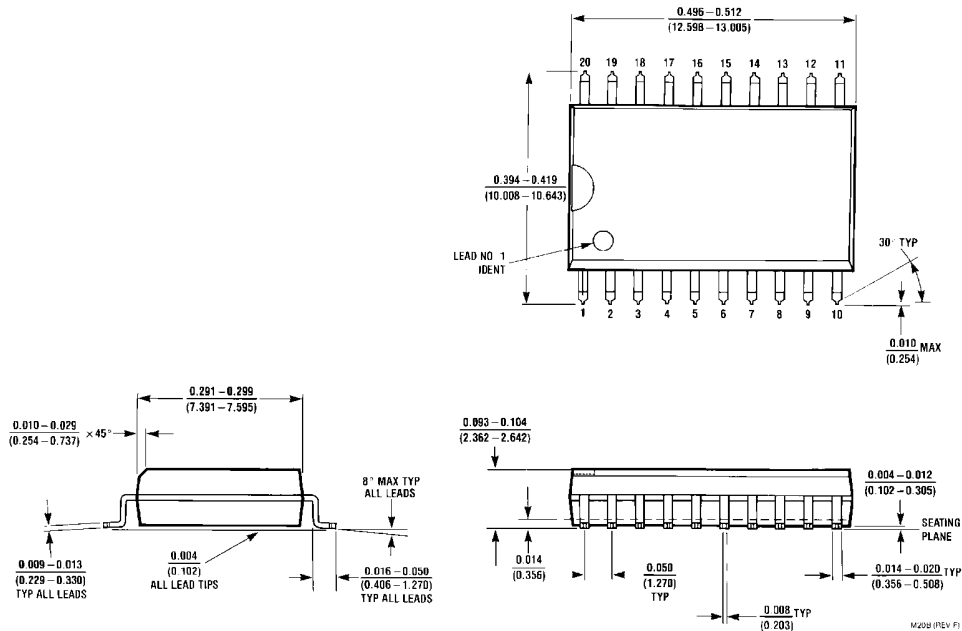


**3-STATE Output HIGH and LOW Enable and Disable Times**



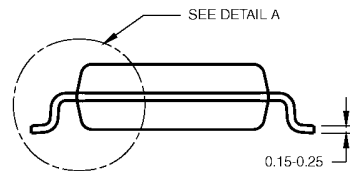
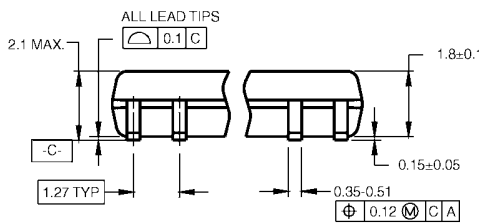
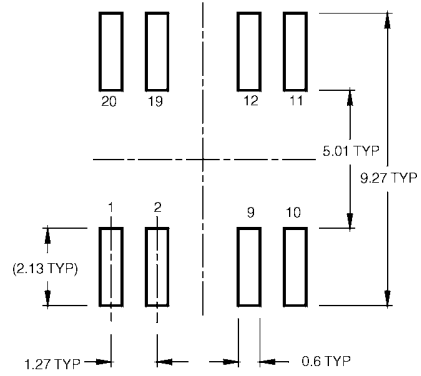
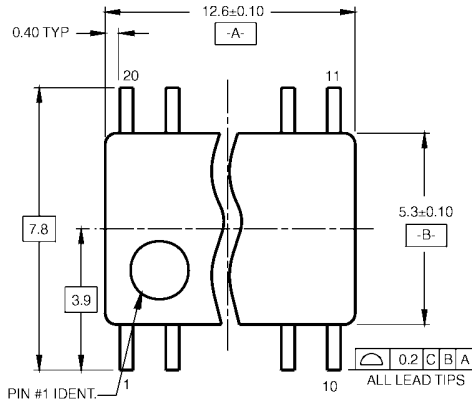
**Setup Time, Hold Time and Recovery Time Waveforms**

**Physical Dimensions** inches (millimeters) unless otherwise noted



**20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide Body Package Number M20B**

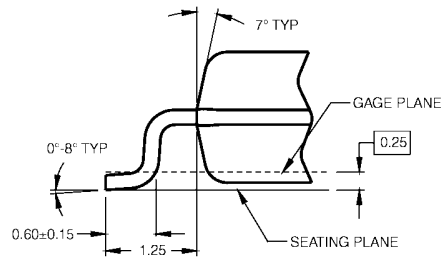
**Physical Dimensions** inches (millimeters) unless otherwise noted (Continued)



DIMENSIONS ARE IN MILLIMETERS

- NOTES:  
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 B. DIMENSIONS ARE IN MILLIMETERS.  
 C. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.

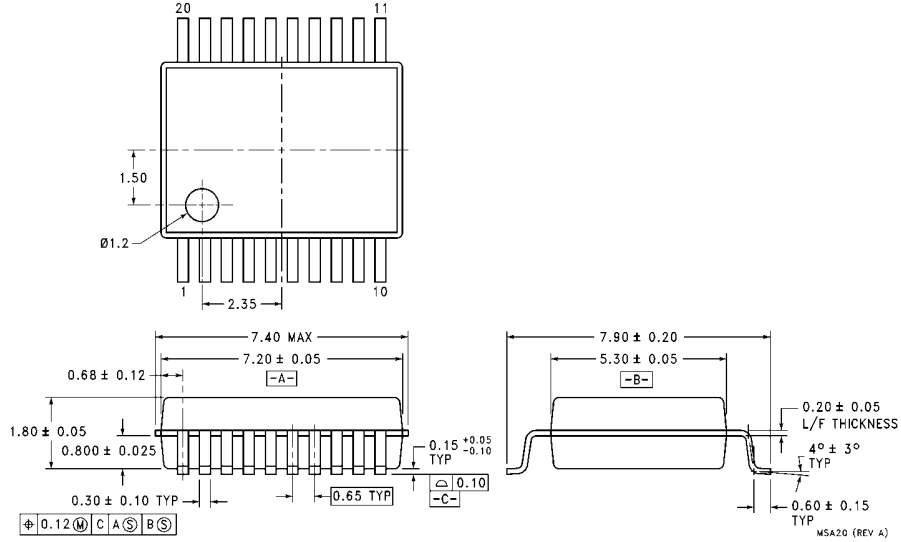
M20DRRevB1



DETAIL A

**20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide Package Number M20D**

**Physical Dimensions** inches (millimeters) unless otherwise noted (Continued)



**20-Lead Shrink Small Outline Package (SSOP), EIAJ TYPE II, 5.3mm Wide  
Package Number MSA20**

**Physical Dimensions** inches (millimeters) unless otherwise noted (Continued)

PIN #1 IDENT.

ALL LEAD TIPS

LAND PATTERN RECOMMENDATION

SEE DETAIL A

DETAIL A

DIMENSIONS ARE IN MILLIMETERS

NOTES:

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D. DIMENSIONS AND TOLERANCES PER ANS Y14.5M, 1982.

MTC20RevD1

**20-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide Package Number MTC20**

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